## 16. TEST SETUP PHOTOGRAPHS

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Figure 16-1 Test Setup for Wireless Device

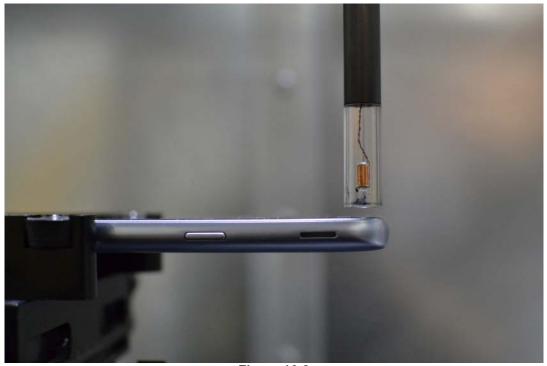


Figure 16-2 Test Setup for Wireless Device

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Figure 16-3 T-Coil Scan Overlay Magnetic Field Distributions

Note: Final measurement locations are indicated by a cursor on the contour plots.

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